

Notice of References Cited

Application/Continuation No.

09/921,786

Applicant(s)/Patent Under
Reexamination
DREVILLON ET AL.

Examiner

Carlos Ortiz-Rodriguez

Art Unit

2125

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kildemo et al., "Real time control of the growth of silicon alloy multilayers by multiwavelength ellipsometry"; Thin Solid Films, Dec. 1996; Vol. 290-291; pages 46-50. ✓
	V	M. Kildemo et al., "A direct robust feedback method for growth control of optical coatings by multiwavelength ellipsometry"; Thin Solid Films, Dec. 1998; Vol. 313-314; pages 484-489. ✓
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.